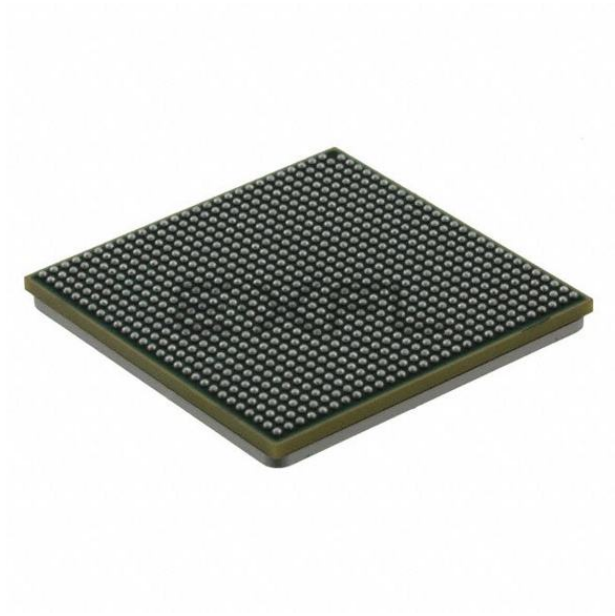

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Understanding Embedded - DSP (Digital Signal Processors)

Embedded - DSP (Digital Signal Processors) are specialized microprocessors designed to perform complex mathematical computations on digital signals in real-time. Unlike general-purpose processors, DSPs are optimized for high-speed numeric processing tasks, making them ideal for applications that require efficient and precise manipulation of digital data. These processors are fundamental in converting and processing signals in various forms, including audio, video, and communication signals, ensuring that data is accurately interpreted and utilized in embedded systems.

Applications of Embedded - DSP (Digital Signal Processors)

Details	
Product Status	Obsolete
Type	SC3850 Dual Core
Interface	Ethernet, I²C, PCI, RGMII, Serial RapidIO, SGMII, SPI, UART/USART
Clock Rate	1GHz
Non-Volatile Memory	ROM (96kB)
On-Chip RAM	576kB
Voltage - I/O	2.50V
Voltage - Core	1.00V
Operating Temperature	0°C ~ 105°C (TJ)
Mounting Type	Surface Mount
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/msc8152sag1000b

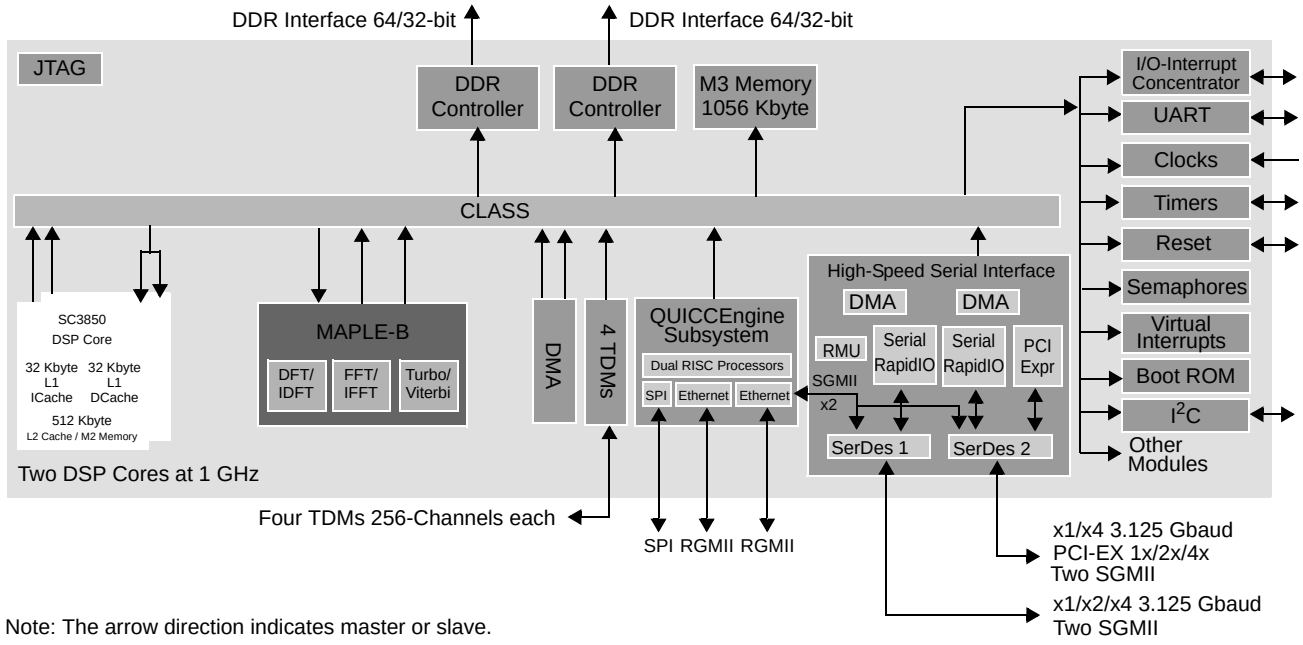


Figure 1. MSC8152 Block Diagram

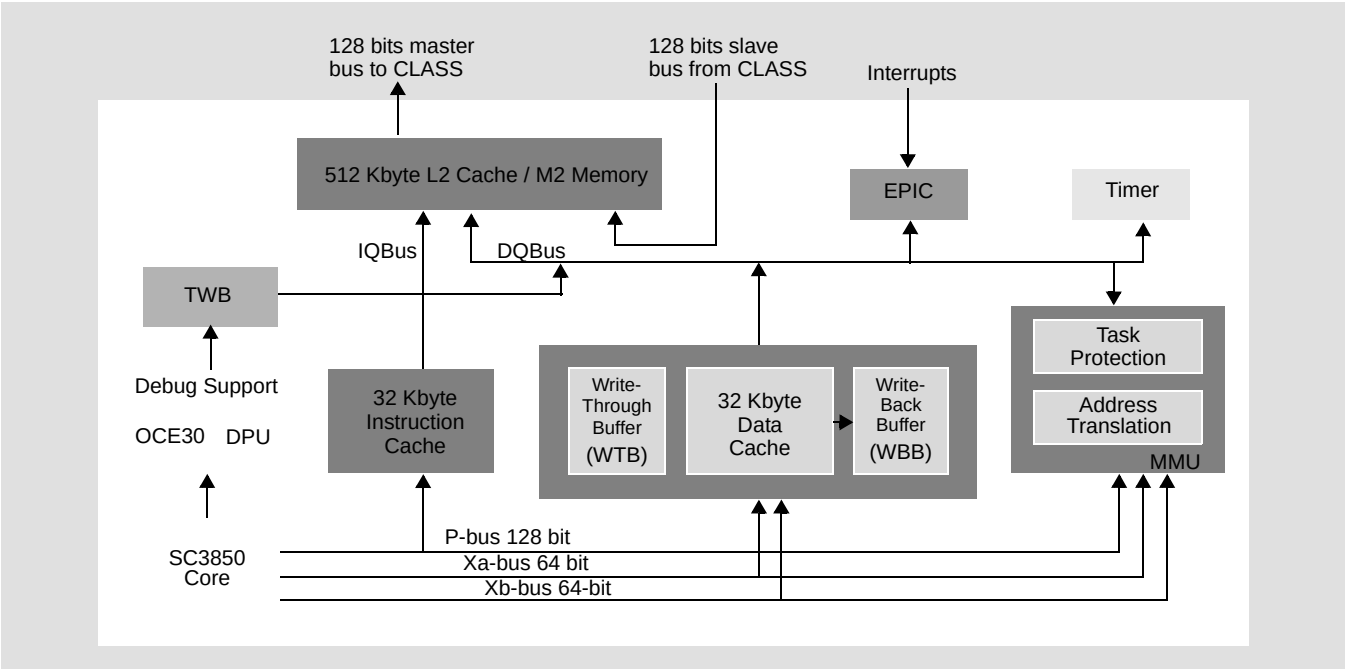


Figure 2. StarCore SC3850 DSP Subsystem Block Diagram

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name[1,2]	Pin Type[10]	Power Rail Name
G7	M2CKE0	O	GVDD2
G8	M2A11	O	GVDD2
G9	M2A7	O	GVDD2
G10	$\overline{\text{M2CK2}}$	O	GVDD2
G11	M2APAR_OUT	O	GVDD2
G12	M2ODT1	O	GVDD2
G13	$\overline{\text{M2APAR\_IN}}$	I	GVDD2
G14	M2DQ43	I/O	GVDD2
G15	M2DM5	O	GVDD2
G16	M2DQ44	I/O	GVDD2
G17	M2DQ40	I/O	GVDD2
G18	M2DQ59	I/O	GVDD2
G19	M2DM7	O	GVDD2
G20	M2DQ60	I/O	GVDD2
G21	Reserved	NC	—
G22	Reserved	NC	—
G23	SXPVSS1	Ground	N/A
G24	SXPVDD1	Power	N/A
G25	SR1_IMP_CAL_TX	I	SXCVDD1
G26	SXCVSS1	Ground	N/A
G27	Reserved	NC	—
G28	Reserved	NC	—
H1	GVDD2	Power	N/A
H2	VSS	Ground	N/A
H3	M2DQ18	I/O	GVDD2
H4	GVDD2	Power	N/A
H5	VSS	Ground	N/A
H6	M2DQ20	I/O	GVDD2
H7	GVDD2	Power	N/A
H8	VSS	Ground	N/A
H9	M2A15	O	GVDD2
H10	M2CK2	O	GVDD2
H11	M2MDIC0	I/O	GVDD2
H12	M2VREF	I	GVDD2
H13	M2MDIC1	I/O	GVDD2
H14	M2DQ46	I/O	GVDD2
H15	M2DQ47	I/O	GVDD2
H16	M2DQ45	I/O	GVDD2
H17	M2DQ41	I/O	GVDD2
H18	M2DQ62	I/O	GVDD2
H19	M2DQ63	I/O	GVDD2
H20	M2DQ61	I/O	GVDD2
H21	Reserved	NC	—
H22	Reserved	NC	—
H23	SR1_TXD3/SG2_TX[4]	O	SXPVDD1
H24	$\overline{\text{SR1\_TXD3}}$/$\overline{\text{SG2\_TX}}$[4]	O	SXPVDD1

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name[1,2]	Pin Type[10]	Power Rail Name
H25	SXCVSS1	Ground	N/A
H26	SXCVDD1	Power	N/A
H27	$\overline{\text{SR1\_RXD3}}$/$\overline{\text{SG2\_RX}}$[4]	I	SXCVDD1
H28	SR1_RXD3/SG2_RX[4]	I	SXCVDD1
J1	M2DQS1	I/O	GVDD2
J2	$\overline{\text{M2DQS1}}$	I/O	GVDD2
J3	M2DQ10	I/O	GVDD2
J4	M2DQ11	I/O	GVDD2
J5	M2DQ14	I/O	GVDD2
J6	M2DQ23	I/O	GVDD2
J7	M2ODT0	O	GVDD2
J8	M2A12	O	GVDD2
J9	M2A14	O	GVDD2
J10	VSS	Ground	N/A
J11	GVDD2	Power	N/A
J12	VSS	Ground	N/A
J13	GVDD2	Power	N/A
J14	VSS	Ground	N/A
J15	GVDD2	Power	N/A
J16	VSS	Ground	N/A
J17	GVDD2	Power	N/A
J18	VSS	Ground	N/A
J19	GVDD2	Power	N/A
J20	Reserved	NC	—
J21	Reserved	NC	—
J22	Reserved	NC	—
J23	SXPVDD1	Power	N/A
J24	SXPVSS1	Ground	N/A
J25	SXCVDD1	Power	N/A
J26	SXCVSS1	Ground	N/A
J27	SXCVDD1	Power	N/A
J28	SXCVSS1	Ground	N/A
K1	VSS	Ground	N/A
K2	GVDD2	Power	N/A
K3	M2DM1	O	GVDD2
K4	VSS	Ground	N/A
K5	GVDD2	Power	N/A
K6	M2DQ0	I/O	GVDD2
K7	VSS	Ground	N/A
K8	GVDD2	Power	N/A
K9	M2DQ5	I/O	GVDD2
K10	VSS	Ground	N/A
K11	VDD	Power	N/A
K12	VSS	Ground	N/A
K13	VDD	Power	N/A
K14	VSS	Ground	N/A

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name[1,2]	Pin Type[10]	Power Rail Name
N23	SR2_TXD2/PE_TXD2/SG1_TX[4]	O	SXPVDD2
N24	$\overline{\text{SR2\_TXD2}}$/$\overline{\text{PE\_TXD2}}$/$\overline{\text{SG1\_TX}}$[4]	O	SXPVDD2
N25	SXCVDD2	Power	N/A
N26	SXCVSS2	Ground	N/A
N27	$\overline{\text{SR2\_RXD2}}$/$\overline{\text{PE\_RXD2}}$/$\overline{\text{SG1\_RX}}$[4]	I	SXCVDD2
N28	SR2_RXD2/PE_RXD2/SG1_RX[4]	I	SXCVDD2
P1	CLKIN	I	QVDD
P2	EE0	I	QVDD
P3	QVDD	Power	N/A
P4	VSS	Ground	N/A
P5	STOP_BS	I	QVDD
P6	QVDD	Power	N/A
P7	VSS	Ground	N/A
P8	PLL0_AVDD[9]	Power	VDD
P9	PLL2_AVDD[9]	Power	VDD
P10	VSS	Ground	N/A
P11	VDD	Power	N/A
P12	VSS	Ground	N/A
P13	VDD	Power	N/A
P14	VSS	Ground	N/A
P15	MVDD	Power	N/A
P16	VSS	Ground	N/A
P17	MVDD	Power	N/A
P18	VSS	Ground	N/A
P19	VDD	Power	N/A
P20	Reserved	NC	—
P21	Reserved	NC	—
P22	Reserved	NC	—
P23	SXPVDD2	Power	N/A
P24	SXPVSS2	Ground	N/A
P25	SR2_PLL_AGND[9]	Ground	SXCVSS2
P26	SR2_PLL_AVDD[9]	Power	SXCVDD2
P27	SXCVSS2	Ground	N/A
P28	SXCVDD2	Power	N/A
R1	VSS	Ground	N/A
R2	$\overline{\text{NMI}}$	I	QVDD
R3	$\overline{\text{NMI\_OUT}}$[6]	O	QVDD
R4	$\overline{\text{HRESET}}$[6,7]	I/O	QVDD
R5	$\overline{\text{INT\_OUT}}$[6]	O	QVDD
R6	EE1	O	QVDD
R7	VSS	Ground	N/A
R8	PLL1_AVDD[9]	Power	VDD
R9	VSS	Ground	N/A
R10	VDD	Power	N/A
R11	VSS	Non-user	N/A
R12	VDD	Power	N/A

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name[1,2]	Pin Type[10]	Power Rail Name
V21	RCW_LSEL_3/RC20	I/O	NVDD
V22	RCW_LSEL_2/RC19	I/O	NVDD
V23	SXPVDD2	Power	N/A
V24	SXPVSS2	Ground	N/A
V25	RCW_LSEL_1/RC18	I/O	NVDD
V26	RC21	I	NVDD
V27	SXCVDD2	Power	N/A
V28	SXCVSS2	Ground	N/A
W1	VSS	Ground	N/A
W2	GVDD1	Power	N/A
W3	M1DM1	O	GVDD1
W4	VSS	Ground	N/A
W5	GVDD1	Power	N/A
W6	M1DQ0	I/O	GVDD1
W7	VSS	Ground	N/A
W8	GVDD1	Power	N/A
W9	M1DQ5	I/O	GVDD1
W10	VDD	Power	N/A
W11	VSS	Ground	N/A
W12	VDD	Power	N/A
W13	VSS	Ground	N/A
W14	VDD	Power	N/A
W15	VSS	Ground	N/A
W16	VDD	Power	N/A
W17	VSS	Ground	N/A
W18	VDD	Power	N/A
W19	VSS	Ground	N/A
W20	VSS	Ground	N/A
W21	RCW_LSEL0/RC17	I/O	NVDD
W22	GPIO19/SPI_MISO[5,8]	I/O	NVDD
W23	VSS	Ground	N/A
W24	NVDD	Power	N/A
W25	GPIO11/IRQ11/RC11[5,8]	I/O	NVDD
W26	GPIO3/DRQ1/IRQ3/RC3[5,8]	I/O	NVDD
W27	GPIO7/IRQ7/RC7[5,8]	I/O	NVDD
W28	GPIO2/IRQ2/RC2[5,8]	I/O	NVDD
Y1	M1DQS1	I/O	GVDD1
Y2	M1DQS1	I/O	GVDD1
Y3	M1DQ10	I/O	GVDD1
Y4	M1DQ11	I/O	GVDD1
Y5	M1DQ14	I/O	GVDD1
Y6	M1DQ23	I/O	GVDD1
Y7	M1ODT0	O	GVDD1
Y8	M1A12	O	GVDD1
Y9	M1A14	O	GVDD1
Y10	VSS	Ground	N/A

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name[1,2]	Pin Type[10]	Power Rail Name
AC19	VSS	Ground	N/A
AC20	GVDD1	Power	N/A
AC21	VSS	Ground	N/A
AC22	NVDD	Power	N/A
AC23	GPIO30/I2C_SCL[5,8]	I/O	NVDD
AC24	GPIO26/TMR3[5,8]	I/O	NVDD
AC25	VSS	Ground	N/A
AC26	NVDD	Power	N/A
AC27	GPIO23/TMR0[5,8]	I/O	NVDD
AC28	GPIO22[5,8]	I/O	NVDD
AD1	M1DQ31	I/O	GVDD1
AD2	M1DQ30	I/O	GVDD1
AD3	M1DQ27	I/O	GVDD1
AD4	M1ECC7	I/O	GVDD1
AD5	M1ECC6	I/O	GVDD1
AD6	M1ECC3	I/O	GVDD1
AD7	M1A9	O	GVDD1
AD8	M1A6	O	GVDD1
AD9	M1A3	O	GVDD1
AD10	M1A10	O	GVDD1
AD11	$\overline{\text{M1RAS}}$	O	GVDD1
AD12	M1A2	O	GVDD1
AD13	M1DQ38	I/O	GVDD1
AD14	$\overline{\text{M1DQS}}$5	I/O	GVDD1
AD15	M1DQS5	I/O	GVDD1
AD16	M1DQ33	I/O	GVDD1
AD17	M1DQ56	I/O	GVDD1
AD18	M1DQ57	I/O	GVDD1
AD19	$\overline{\text{M1DQS7}}$	I/O	GVDD1
AD20	M1DQS7	I/O	GVDD1
AD21	VSS	Ground	N/A
AD22	GE2_TX_CTL	O	NVDD
AD23	GPIO15/DDN0/$\overline{\text{IRQ15}}$/RC15[5,8]	I/O	NVDD
AD24	GPIO13/$\overline{\text{IRQ13}}$/RC13[5,8]	I/O	NVDD
AD25	GE_MDC	O	NVDD
AD26	GE_MDIO	I/O	NVDD
AD27	TDM2TCK/GE1_TD3[3]	I/O	NVDD
AD28	TDM2RCK/GE1_TD0[3]	I/O	NVDD
AE1	GVDD1	Power	N/A
AE2	VSS	Ground	N/A
AE3	M1DQ29	I/O	GVDD1
AE4	GVDD1	Power	N/A
AE5	VSS	Ground	N/A
AE6	M1ECC5	I/O	GVDD1
AE7	GVDD1	Power	N/A
AE8	VSS	Ground	N/A

2.2 Recommended Operating Conditions

Table 3 lists recommended operating conditions. Proper device operation outside of these conditions is not guaranteed.

Table 3. Recommended Operating Conditions

Rating	Symbol	Min	Nominal	Max	Unit
Core supply voltage	V_{DD}	0.97	1.0	1.05	V
M3 memory supply voltage	V_{DDM3}	0.97	1.0	1.05	V
MAPLE-B supply voltage	V_{DDM}	0.97	1.0	1.05	V
DDR memory supply voltage • DDR2 mode • DDR3 mode DDR reference voltage	V_{DDDDR} MV_{REF}	 1.7 1.425 $0.49 \times V_{DDDDR}$	 1.8 1.5 $0.5 \times V_{DDDDR}$	 1.9 1.575 $0.51 \times V_{DDDDR}$	 V V V
I/O voltage excluding DDR and RapidIO lines	V_{DDIO}	2.375	2.5	2.625	V
Rapid I/O pad voltage	V_{DDSXP}	0.97	1.0	1.05	V
Rapid I/O core voltage	V_{DDSXC}	0.97	1.0	1.05	V
Operating temperature range: • Standard • Higher • Extended	 T_J T_J T_A T_J	 0 0 –40 —		 90 105 — 105	 °C °C °C

2.5.1.2 DDR3 (1.5V) SDRAM DC Electrical Characteristics

Table 7 provides the recommended operating conditions for the DDR SDRAM controller when interfacing to DDR3 SDRAM.

Note: At recommended operating conditions (see Table 3) with V_{DDDDR} = 1.5 V.

Table 7. DDR3 SDRAM Interface DC Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O reference voltage	MV_{REF}	0.49 × V_{DDDDR}	0.51 × V_{DDDDR}	V	2,3,4
Input high voltage	V_{IH}	MV_{REF} + 0.100	V_{DDDDR}	V	5
Input low voltage	V_{IL}	GND	MV_{REF} – 0.100	V	5
I/O leakage current	I_{OZ}	–50	50	μA	6

Notes:
1. V_{DDDDR} is expected to be within 50 mV of the DRAM V_{DD} at all times. The DRAM and memory controller can use the same or different sources.
2. MV_{REF} is expected to be equal to 0.5 × V_{DDDDR}, and to track V_{DDDDR} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed ±1% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF} with a minimum value of MV_{REF} – 0.4 and a maximum value of MV_{REF} + 0.04 V. V_{TT} should track variations in the DC-level of MV_{REF}.
4. The voltage regulator for MV_{REF} must be able to supply up to 250 μA.
5. Input capacitance load for DQ, DQS, and $\overline{DQS}$ signals are available in the IBIS models.
6. Output leakage is measured with all outputs are disabled, 0 V ≤ V_{OUT} ≤ V_{DDDDR}.

2.5.1.3 DDR2/DDR3 SDRAM Capacitance

Table 8 provides the DDR controller interface capacitance for DDR2 and DDR3 memory.

Note: At recommended operating conditions (see Table 3) with V_{DDDDR} = 1.8 V for DDR2 memory or V_{DDDDR} = 1.5 V for DDR3 memory.

Table 8. DDR2/DDR3 SDRAM Capacitance

Parameter	Symbol	Min	Max	Unit
I/O capacitance: DQ, DQS, $\overline{DQS}$	C_{IO}	6	8	pF
Delta I/O capacitance: DQ, DQS, $\overline{DQS}$	C_{DIO}	—	0.5	pF

Note: Guaranteed by FAB process and micro-construction.

2.5.2.2 SerDes Reference Clock Receiver Characteristics

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clock inputs are SR1_REF_CLK/$\overline{\text{SR1\_REF\_CLK}}$ or SR2_REF_CLK/$\overline{\text{SR2\_REF\_CLK}}$. Figure 5 shows a receiver reference diagram of the SerDes reference clocks.

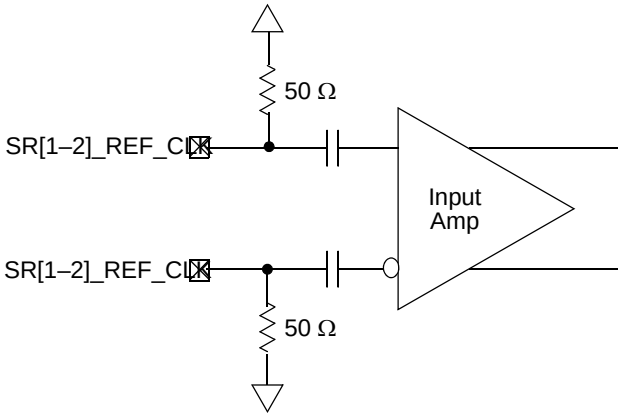


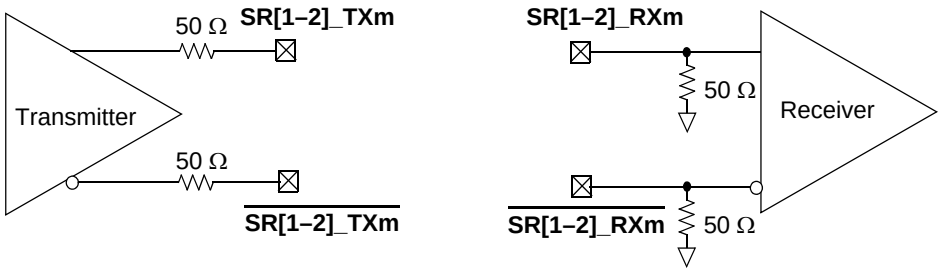
Figure 5. Receiver of SerDes Reference Clocks

The characteristics of the clock signals are as follows:

- The supply voltage requirements for V_{DDSXC} are as specified in **Table 3.**
- The SerDes reference clock receiver reference circuit structure is as follows:
  - The SR[1–2]_REF_CLK and $\overline{\text{SR[1–2]\_REF\_CLK}}$ are internally AC-coupled differential inputs as shown in Figure 5. Each differential clock input (SR[1–2]_REF_CLK or $\overline{\text{SR[1–2]\_REF\_CLK}}$) has on-chip 50-Ω termination to GND_{SXC} followed by on-chip AC-coupling.
  - The external reference clock driver must be able to drive this termination.
  - The SerDes reference clock input can be either differential or single-ended. Refer to the differential mode and single-ended mode descriptions below for detailed requirements.
- The maximum average current requirement also determines the common mode voltage range.
  - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA because the input is AC-coupled on-chip.
  - This current limitation sets the maximum common mode input voltage to be less than 0.4 V (0.4 V / 50 = 8 mA) while the minimum common mode input level is 0.1 V above GND_{SXC}. For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0–0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
  - If the device driving the SR[1–2]_REF_CLK and $\overline{\text{SR[1–2]\_REF\_CLK}}$ inputs cannot drive 50 Ω to GND_{SXC} DC or the drive strength of the clock driver chip exceeds the maximum input current limitations, it must be AC-coupled externally.
- The input amplitude requirement is described in detail in the following sections.

2.5.2.3 SerDes Transmitter and Receiver Reference Circuits

Figure 6 shows the reference circuits for SerDes data lane transmitter and receiver.



Note: The [1–2] indicates the specific SerDes Interface (1 or 2) and the m indicates the specific channel within that interface (0,1,2,3). Actual signals are assigned by the HRCW assignments at reset (see **Chapter 5**, *Reset* in the reference manual for details)

Figure 6. SerDes Transmitter and Receiver Reference Circuits

2.5.3 DC-Level Requirements for SerDes Interfaces

The following subsections define the DC-level requirements for the SerDes reference clocks, the PCI Express data lines, the Serial RapidIO data lines, and the SGMII data lines.

2.5.3.1 DC-Level Requirements for SerDes Reference Clocks

The DC-level requirement for the SerDes reference clock inputs is different depending on the signaling mode used to connect the clock driver chip and SerDes reference clock inputs, as described below:

- Differential Mode
  - The input amplitude of the differential clock must be between 400 mV and 1600 mV differential peak-peak (or between 200 mV and 800 mV differential peak). In other words, each signal wire of the differential pair must have a single-ended swing of less than 800 mV and greater than 200 mV. This requirement is the same for both external DC-coupled or AC-coupled connection.
  - For an external DC-coupled connection, the maximum average current requirements sets the requirement for average voltage (common mode voltage) as between 100 mV and 400 mV. Figure 7 shows the SerDes reference clock input requirement for DC-coupled connection scheme.

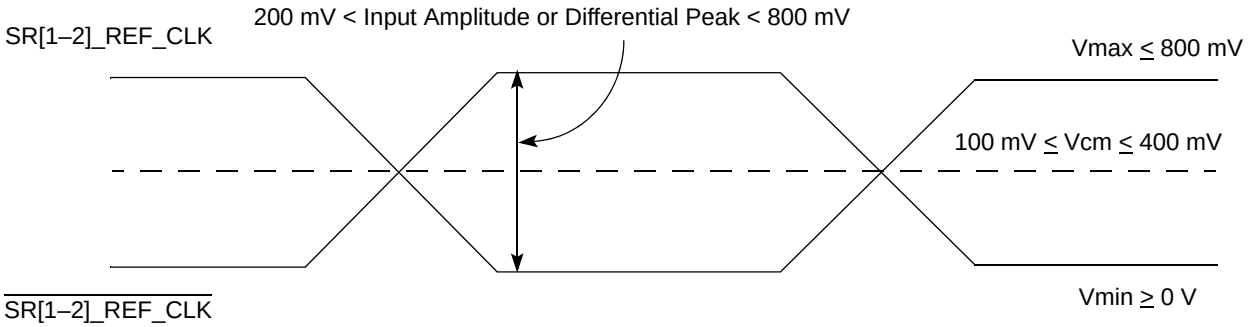


Figure 7. Differential Reference Clock Input DC Requirements (External DC-Coupled)

Table 22 provides the DDR2 differential specifications for the differential signals MDQS/$\overline{\text{MDQS}}$ and MCK/$\overline{\text{MCK}}$.

Table 22. DDR2 SDRAM Differential Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Input AC differential cross-point voltage	V_{IXAC}	0.5 × GVDD – 0.175	0.5 × GVDD + 0.175	V
Output AC differential cross-point voltage	V_{OXAC}	0.5 × GVDD – 0.125	0.5 × GVDD + 0.125	V

Table 23 provides the DDR3 differential specifications for the differential signals MDQS/$\overline{\text{MDQS}}$ and MCK/$\overline{\text{MCK}}$.

Table 23. DDR3 SDRAM Differential Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Input AC differential cross-point voltage	V_{IXAC}	0.5 × GVDD – 0.150	0.5 × GVDD + 0.150	V
Output AC differential cross-point voltage	V_{OXAC}	0.5 × GVDD – 0.115	0.5 × GVDD + 0.115	V

2.6.2 HSSI AC Timing Specifications

The following subsections define the AC timing requirements for the SerDes reference clocks, the PCI Express data lines, the Serial RapidIO data lines, and the SGMII data lines.

2.6.2.1 AC Requirements for SerDes Reference Clock

Table 24 lists AC requirements for the SerDes reference clocks.

Note: Specifications are valid at the recommended operating conditions listed in Table 3.

Table 24. SR[1–2]_REF_CLK and $\overline{\text{SR[1–2]\_REF\_CLK}}$ Input Clock Requirements

Parameter	Symbol	Min	Typical	Max	Units	Notes
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ frequency range	t_{CLK_REF}	—	100/125	—	MHz	1
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ clock frequency tolerance	t_{CLK_TOL}	–350	—	350	ppm	—
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ reference clock duty cycle (measured at 1.6 V)	t_{CLK_DUTY}	40	50	60	%	—
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ max deterministic peak-peak jitter at 10^{-6} BER	t_{CLK_DJ}	—	—	42	ps	—
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ total reference clock jitter at 10^{-6} BER (peak-to-peak jitter at ref_clk input)	t_{CLK_TJ}	—	—	86	ps	2
SR[1–2]_REF_CLK/$\overline{\text{SR[1–2]\_REF\_CLK}}$ rising/falling edge rate	t_{CLKRR}/t_{CLKFR}	1	—	4	V/ns	3
Differential input high voltage	V_{IH}	200	—	—	mV	4
Differential input low voltage	V_{IL}	—	—	–200	mV	4
Rising edge rate (SR[1–2]_REF_CLK) to falling edge rate (SR[1–2]_REF_CLK) matching	Rise-Fall Matching	—	—	20	%	5, 6

2.6.2.4 SGMII AC Timing Specifications

Note: Specifications are valid at the recommended operating conditions listed in Table 3.

Transmitter and receiver AC characteristics are measured at the transmitter outputs (SR[1–2]_TX[n] and $\overline{\text{SR[1–2]\_TX}}$[n]) or at the receiver inputs (SR[1–2]_RX[n] and $\overline{\text{SR[1–2]\_RX}}$[n]) as depicted in Figure 19, respectively.

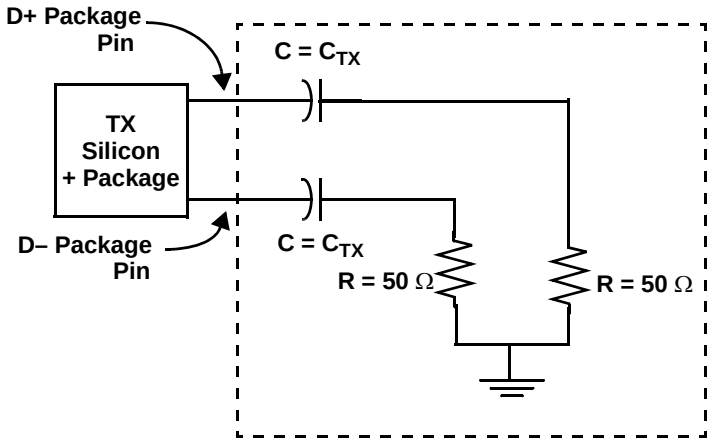


Figure 19. SGMII AC Test/Measurement Load

Table 29 provides the SGMII transmit AC timing specifications. A source synchronous clock is not supported. The AC timing specifications do not include REF_CLK jitter.

Table 29. SGMII Transmit AC Timing Specifications

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter	JD	—	—	0.17	UI p-p	—
Total Jitter	JT	—	—	0.35	UI p-p	2
Unit Interval	UI	799.92	800	800.08	ps	1

Notes: 1. See Figure 18 for single frequency sinusoidal jitter limits
2. Each UI is 800 ps ± 100 ppm.

Table 30 provides the SGMII receiver AC timing specifications. The AC timing specifications do not include REF_CLK jitter.

Table 30. SGMII Receive AC Timing Specifications

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter Tolerance	JD	0.37	—	—	UI p-p	1, 2
Combined Deterministic and Random Jitter Tolerance	JDR	0.55	—	—	UI p-p	1, 2
Total Jitter Tolerance	JT	0.65	—	—	UI p-p	1,2
Bit Error Ratio	BER	—	—	10^{-12}	—	—
Unit Interval	UI	799.92	800.00	800.08	ps	3

Notes: 1. Measured at receiver.
2. Refer to RapidIO™ 1x/4x LP Serial Physical Layer Specification for interpretation of jitter specifications. Also see Figure 18.
3. Each UI is 800 ps ± 100 ppm.

2.6.3 TDM Timing

Table 31 provides the input and output AC timing specifications for the TDM interface.

Table 31. TDM AC Timing Specifications for 62.5 MHz[1]

Parameter	Symbol[2]	Min	Max	Unit
TDMxRCK/TDMxTCK	t_{DM}	16.0	—	ns
TDMxRCK/TDMxTCK high pulse width	t_{DM_HIGH}	7.0	—	ns
TDMxRCK/TDMxTCK low pulse width	t_{DM_LOW}	7.0	—	ns
TDM all input setup time	t_{DMIVKH}	3.6	—	ns
TDMxRD hold time	$t_{DMRDIXKH}$	1.9	—	ns
TDMxTFS/TDMxRFS input hold time	$t_{DMFSIXKH}$	1.9	—	ns
TDMxTCK High to TDMxTD output active	t_{DM_OUTAC}	2.5	—	ns
TDMxTCK High to TDMxTD output valid	$t_{DMTKHOV}$	—	9.8	ns
TDMxTD hold time	$t_{DMTKHOX}$	2.5	—	ns
TDMxTCK High to TDMxTD output high impedance	t_{DM_OUTHI}	—	9.8	ns
TDMxTFS/TDMxRFS output valid	$t_{DMFSKHOV}$	—	9.25	ns
TDMxTFS/TDMxRFS output hold time	$t_{DMFSKHOX}$	2.0	—	ns

Notes:
1. The symbols used for timing specifications follow the pattern $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{HIKHOX} symbolizes the output internal timing (HI) for the time t_{serial} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).
2. Output values are based on 30 pF capacitive load.
3. Inputs are referenced to the sampling that the TDM is programmed to use. Outputs are referenced to the programming edge they are programmed to use. Use of the rising edge or falling edge as a reference is programmable. T_{DMxTCK} and T_{DMxRCK} are shown using the rising edge.
4. All values are based on a maximum TDM interface frequency of 62.5 MHz.

Figure 20 shows the TDM receive signal timing.

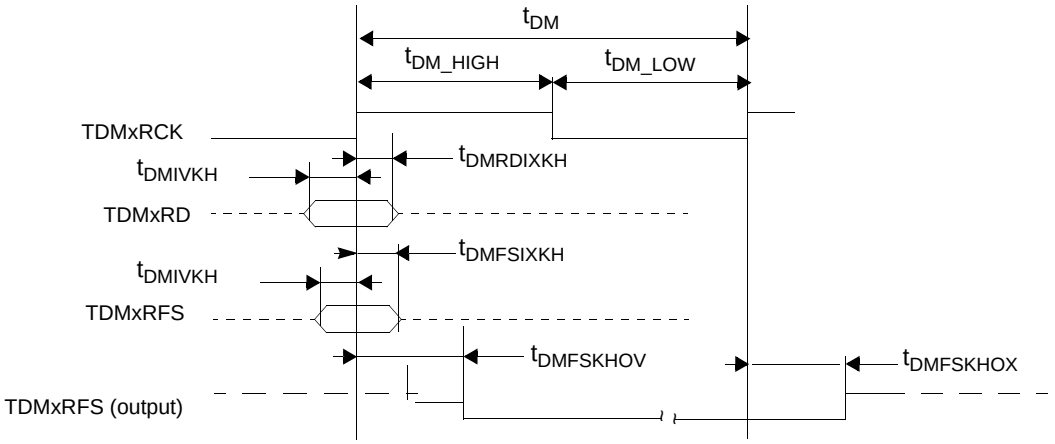


Figure 20. TDM Receive Signals

Figure 21 shows the TDM transmit signal timing.

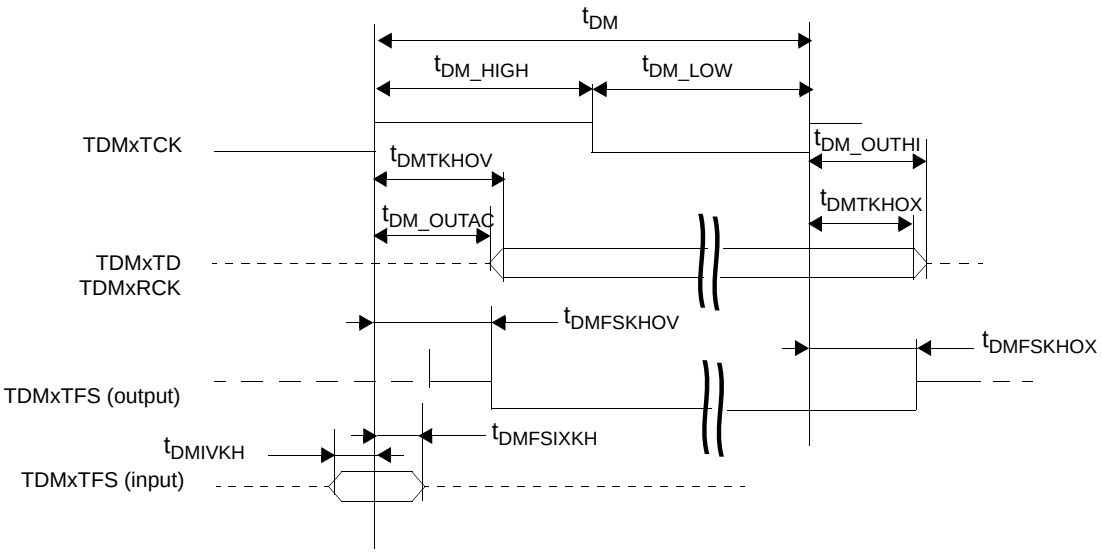


Figure 21. TDM Transmit Signals

Figure 22 provides the AC test load for the TDM/SI.

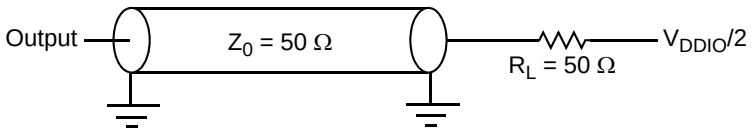


Figure 22. TDM AC Test Load

2.6.4 Timers AC Timing Specifications

Table 32 lists the timer input AC timing specifications.

Table 32. Timers Input AC Timing Specifications

Characteristics	Symbol	Minimum	Unit	Notes
Timers inputs—minimum pulse width	T_{TIWID}	8	ns	1, 2

Notes:
1. The maximum allowed frequency of timer outputs is 125 MHz. Configure the timer modules appropriately.
2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by any external synchronous logic. Timer inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

Note: For recommended operating conditions, see Table 3.

Figure 23 shows the AC test load for the timers.

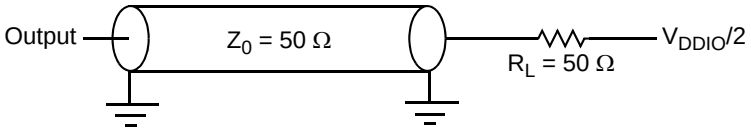


Figure 23. Timer AC Test Load

2.6.6 SPI Timing

Table 36 lists the SPI input and output AC timing specifications.

Table 36. SPI AC Timing Specifications

Parameter	Symbol [1]	Min	Max	Unit	Note
SPI outputs valid—Master mode (internal clock) delay	t_{NIKHOV}	—	6	ns	2
SPI outputs hold—Master mode (internal clock) delay	t_{NIKHOX}	0.5	—	ns	2
SPI outputs valid—Slave mode (external clock) delay	t_{NEKHOV}	—	12	ns	2
SPI outputs hold—Slave mode (external clock) delay	t_{NEKHOX}	2	—	ns	2
SPI inputs—Master mode (internal clock) input setup time	t_{NIIVKH}	12	—	ns	—
SPI inputs—Master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns	—
SPI inputs—Slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns	—
SPI inputs—Slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns	—

Notes:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOX} symbolizes the internal timing (NI) for the time SPICLK clock reference (K) goes to the high state (H) until outputs (O) are invalid (X).
2. Output specifications are measured from the 50% level of the rising edge of SPICLK to the 50% level of the signal. Timings are measured at the pin.

Figure 26 provides the AC test load for the SPI.

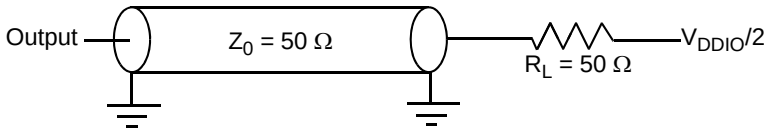
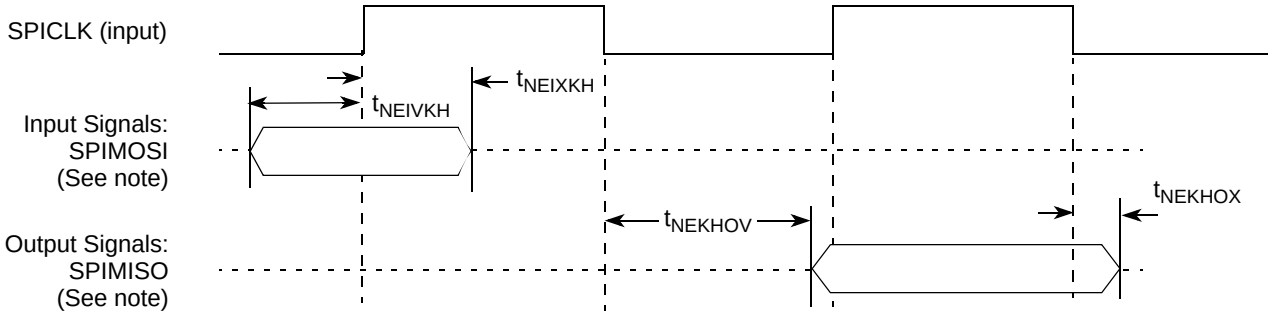


Figure 26. SPI AC Test Load

Figure 27 and Figure 28 represent the AC timings from Table 36. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

Figure 27 shows the SPI timings in slave mode (external clock).



Note: measured with SPMODE[CI] = 0, SPMODE[CP] = 0

Figure 27. SPI AC Timing in Slave Mode (External Clock)

Figure 28 shows the SPI timings in master mode (internal clock).

2.6.7 Asynchronous Signal Timing

Table 35 lists the asynchronous signal timing specifications.

Table 37. Signal Timing

Characteristics	Symbol	Type	Min
Input	t_{IN}	Asynchronous	One CLKIN cycle
Output	t_{OUT}	Asynchronous	Application dependent
Note: Input value relevant for EE0, $\overline{\text{IRQ}}$[15–0], and $\overline{\text{NMI}}$ only.			

The following interfaces use the specified asynchronous signals:

- *GPIO*. Signals GPIO[31–0], when used as GPIO signals, that is, when the alternate multiplexed special functions are not selected.

Note: When used as a general purpose input (GPI), the input signal should be driven until it is acknowledged by the MSC8152 device, that is, when the expected input value is read from the GPIO data register.

- *EE port*. Signals EE0, EE1.
- *Boot function*. Signal STOP_BS.
- *I^2C interface*. Signals I2C_SCL and I2C_SDA.
- *Interrupt inputs*. Signals $\overline{\text{IRQ}}$[15–0] and $\overline{\text{NMI}}$.
- *Interrupt outputs*. Signals $\overline{\text{INT\_OUT}}$ and $\overline{\text{NMI\_OUT}}$ (minimum pulse width is 32 ns).

2.6.8 JTAG Signals

Table 38 lists the JTAG timing specifications shown in Figure 29 through Figure 32.

Table 38. JTAG Timing

Characteristics	Symbol	All frequencies		Unit
		Min	Max	
TCK cycle time	t_{TCKX}	36.0	—	ns
TCK clock high phase measured at $V_M = V_{DDIO}/2$	t_{TCKH}	15.0	—	ns
Boundary scan input data setup time	t_{BSVKH}	0.0	—	ns
Boundary scan input data hold time	t_{BSXKH}	15.0	—	ns
TCK fall to output data valid	t_{TCKHOV}	—	20.0	ns
TCK fall to output high impedance	t_{TCKHOZ}	—	24.0	ns
TMS, TDI data setup time	t_{TDIVKH}	0.0	—	ns
TMS, TDI data hold time	t_{TDIXKH}	5.0	—	ns
TCK fall to TDO data valid	t_{TDOHOV}	—	10.0	ns
TCK fall to TDO high impedance	t_{TDOHOZ}	—	12.0	ns
$\overline{\text{TRST}}$ assert time	t_{TRST}	100.0	—	ns
Note: All timings apply to OnCE module data transfers as well as any other transfers via the JTAG port.				

Figure 29 shows the test clock input timing diagram

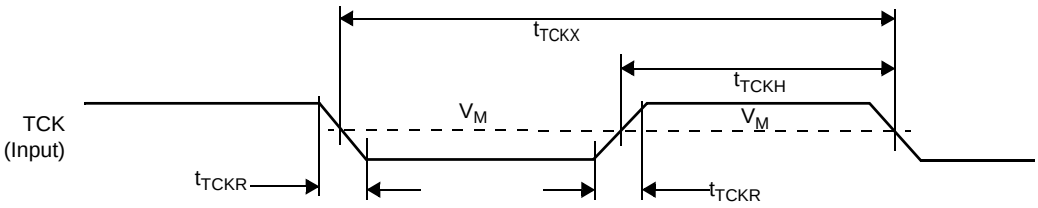


Figure 29. Test Clock Input Timing

Figure 30 shows the boundary scan (JTAG) timing diagram.

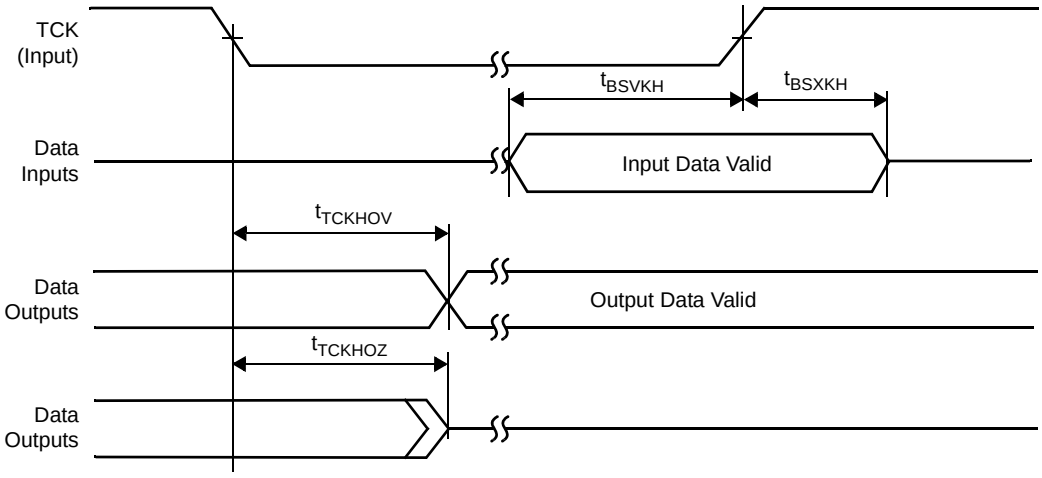


Figure 30. Boundary Scan (JTAG) Timing

Figure 31 shows the test access port timing diagram

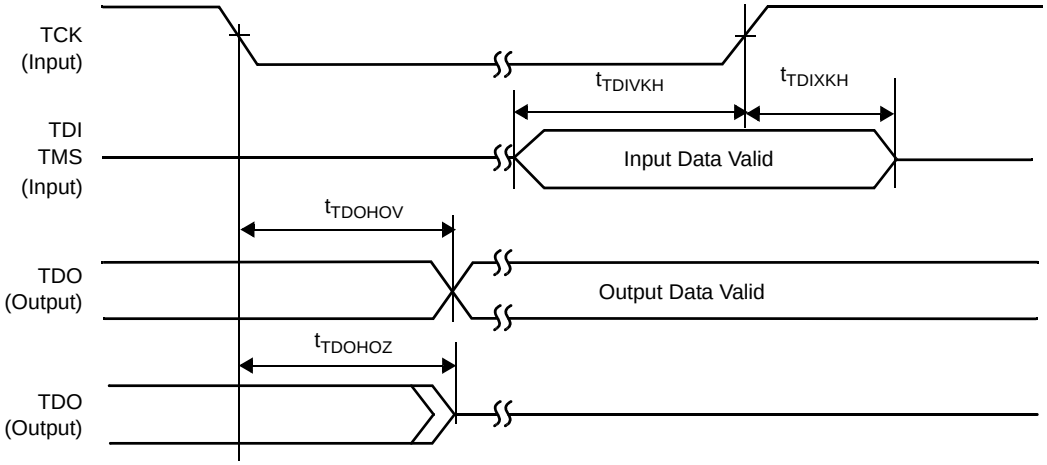


Figure 31. Test Access Port Timing

Figure 32 shows the $\overline{\text{TRST}}$ timing diagram.

Figure 32. $\overline{\text{TRST}}$ Timing

3.5.1 DDR Memory Related Pins

This section discusses the various scenarios that can be used with either of the MSC8152 DDR ports.

Note: The signal names in Table 40, Table 41 and Table 42 are generic names for a DDR SDRAM interface. For actual pin names refer to Table 1.

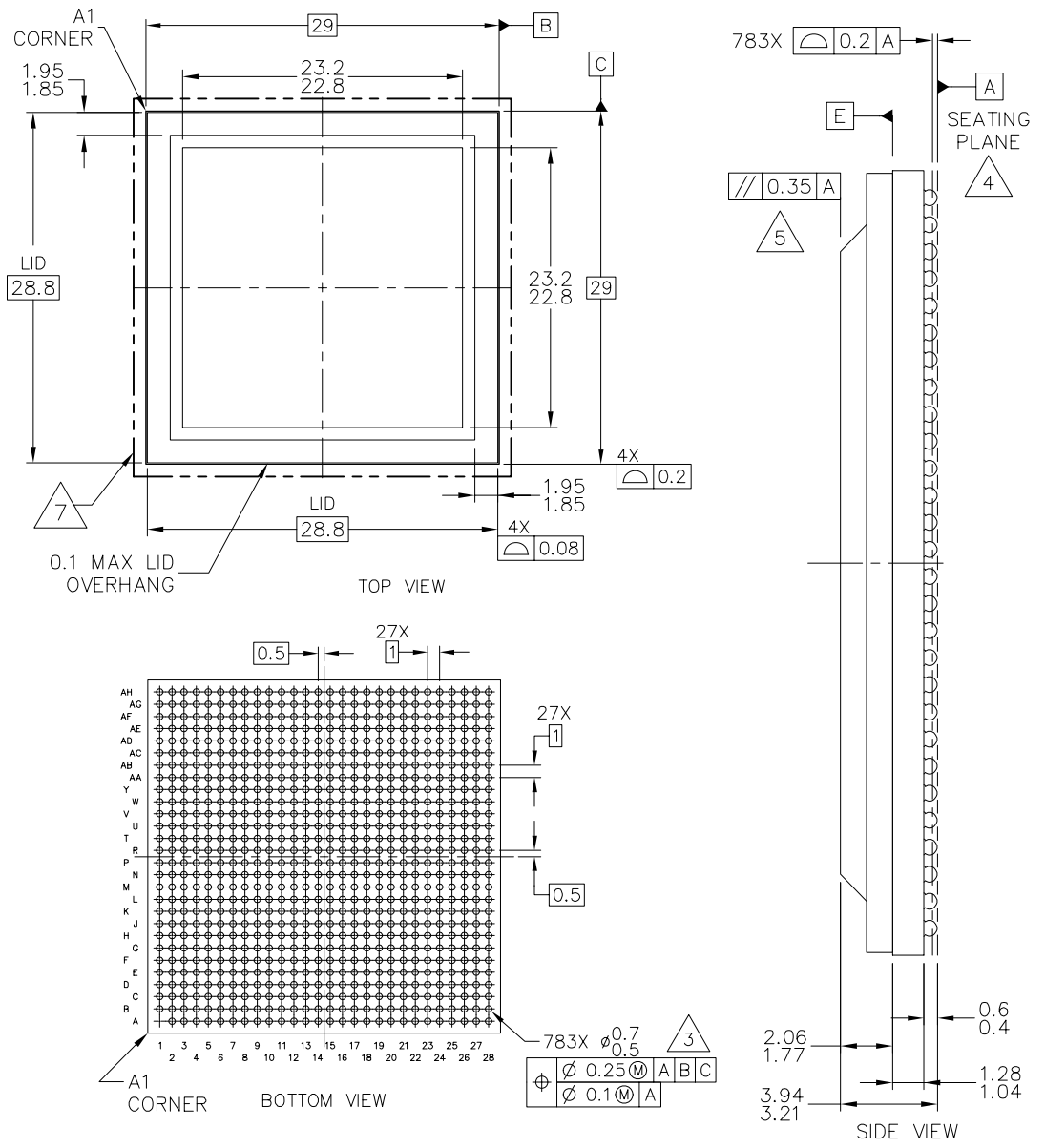
3.5.1.1 DDR Interface Is Not Used

Table 40. Connectivity of DDR Related Pins When the DDR Interface Is Not Used

Signal Name	Pin Connection
MDQ[0–63]	NC
MDQS[7–0]	NC
$\overline{\text{MDQS[7–0]}}$	NC
MA[15–0]	NC
MCK[0–2]	NC
$\overline{\text{MCK[0–2]}}$	NC
$\overline{\text{MCS[1–0]}}$	NC
MDM[7–0]	NC
MBA[2–0]	NC
$\overline{\text{MCAS}}$	NC
MCKE[1–0]	NC
MODT[1–0]	NC
MMDIC[1–0]	NC
$\overline{\text{MRAS}}$	NC
$\overline{\text{MWE}}$	NC
MECC[7–0]	NC
MDM8	NC
MDQS8	NC
$\overline{\text{MDQS8}}$	NC
MAPAR_OUT	NC
$\overline{\text{MAPAR\_IN}}$	NC
MVREF[3]	NC
GVDD1/GVDD2[3]	NC

Notes:
1. For the signals listed in this table, the initial M stands for M1 or M2 depending on which DDR controller is not used.
2. If the DDR controller is not used, disable the internal DDR clock by setting the appropriate bit in the System Clock Control Register (SCCR) and put all DDR I/O in sleep mode by setting DRx_GCR[DDRx_DOZE] (for DDR controller x). See the *Clocks* and *General Configuration Registers* chapters in the ***MSC8152 Reference Manual*** for details.
3. For MSC8152 Revision 1 silicon, these pins were connected to GND. For newer revisions of the MSC8152, connecting these pins to GND increases device power consumption.

5 Package Information



NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURE PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PARALLELISM MEASUREMENT SHALL EXCLUDE ANY EFFECT OF MARK ON TOP SURFACE OF PACKAGE.
6. ALL DIMENSIONS ARE SYMMETRIC ACROSS THE PACKAGE CENTER LINES, UNLESS DIMENSIONED OTHERWISE.
7. 29.2MM MAXIMUM PACKAGE ASSEMBLY (LID + LAMINATE) X AND Y.

Figure 40. MSC8152 Mechanical Information, 783-ball FC-PBGA Package

6 Product Documentation

Following is a general list of supporting documentation:

- *MSC8152 Technical Data Sheet* (MSC8152). Details the signals, AC/DC characteristics, clock signal characteristics, package and pinout, and electrical design considerations of the MSC8152 device.
- *MSC8152 Reference Manual* (MSC8152RM). Includes functional descriptions of the extended cores and all the internal subsystems including configuration and programming information.
- *Application Notes*. Cover various programming topics related to the StarCore DSP core and the MSC8152 device.
- *QUICC Engine Block Reference Manual with Protocol Interworking* (QEIWRM). Provides detailed information regarding the QUICC Engine technology including functional description, registers, and programming information.
- *SC3850 DSP Core Reference Manual*. Covers the SC3850 core architecture, control registers, clock registers, program control, and instruction set.
- *MSC8156SC3850 DSP Core Subsystem Reference Manual*. Covers core subsystem architecture, functionality, and registers.

7 Revision History

Table 50 provides a revision history for this data sheet.

Table 50. Document Revision History

Rev.	Date	Description
0	Jun. 2010	• Initial public release.
1	Dec 2010	• Updated Table 16. • Updated **Section 3.1.2**, *Power-On Ramp Time*.
2	Mar 2011	• Updated Table 8. • Updated Table 15. • Updated Table 17. • Updated Table 33. • Updated Table 35. • Updated Table 39.
3	May 2011	• Updated Table 1. Changed the pin types for the following: – F25 from ground to power. – F26 from power to ground. – T6 from power to O.
4	Oct 2011	• Updated Table 34 and Table 35 to reflect 1 Gbps and 100 Mbps data rate instead of 1 GHz and 100 MHz.
5	Dec 2011	• Added note 4 to Table 39.
6	Aug 2013	• Updated Section 4, “Ordering Information”.